

Electrochemical preparation of nanotips

Automated etching device ARMIN



Institute of Scientific
Instruments
The Czech Academy
of Sciences

APPLICATIONS

The fully automated etching device enables end-users to easily create ultra-sharp nanotips of diameters lower than 50 nanometers on a single- or poly-crystalline wires.

Main features

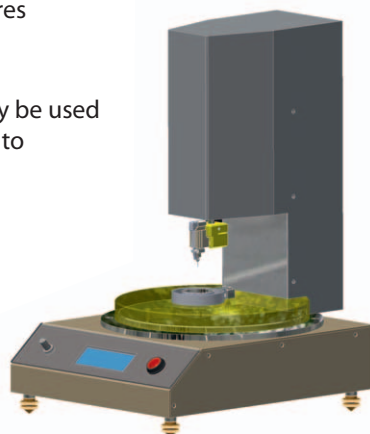
- Fully automated compact solution offering high reproducibility
- Storage memory for various etching procedures

Extended etching options

- Single-crystalline or poly-crystalline wires may be used
- Variability of wire diameters used (0.1 mm up to 0.35 mm)
- Customized tip shape

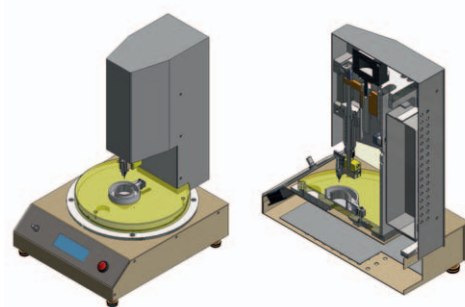
Examples of use

- Scanning Tunneling Microscopy (STM) probes
- Nanomanipulators (FIB and SEM)
- Field Emission (FE) cathodes



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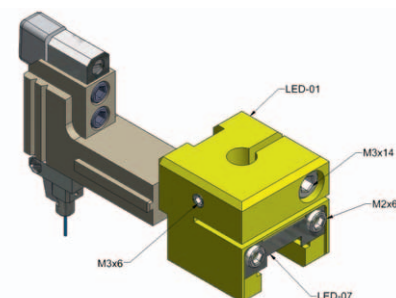
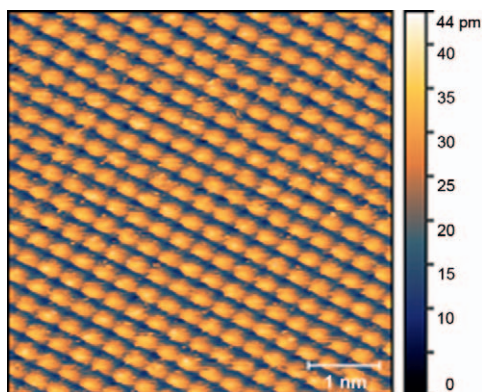
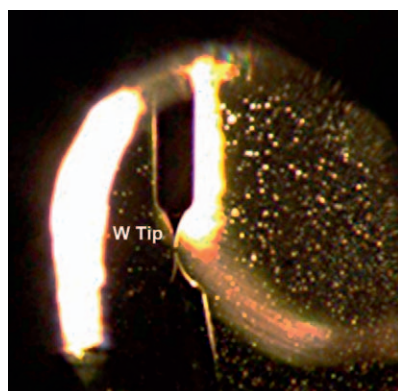


Advanced mechanical construction
containing digital and analogue
parts for real-time process control
and measurement.

CASE STUDY 1

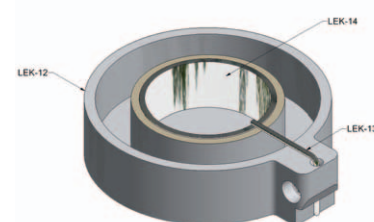
Scanning Tunneling Microscopy (STM) Probe

The STM tips were formed from 0.3 mm tungsten wire. The image below (left) shows the scanning probe above the planar surface of the silver, showed in better detail (right).



Plug-in adaptor containing special
clamp holding etched wire. Can be
easily removed or switched for another.

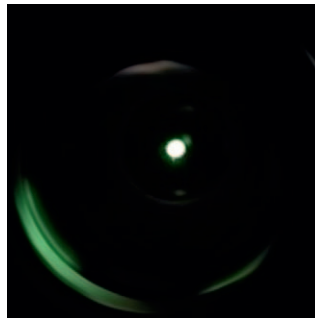
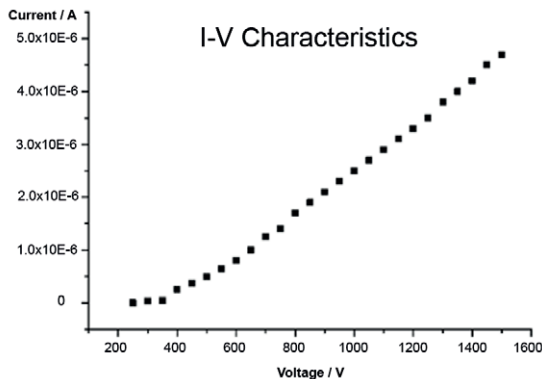
Plug-in plastic cylinder serving as an
electrolyte tank. Can be easily removed
or switched for another.



CASE STUDY 2

Cold Field Emission Cathode

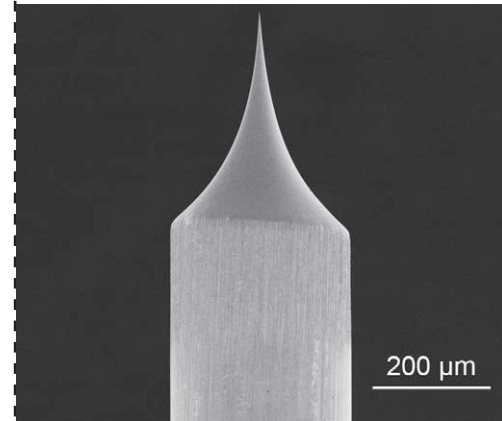
Sharp tips with low apex radius are important for cathodes based on field emission (FE) of electrons. The need for them arose in the early days of electron microscopy, especially in connection with field emission microscopy (FEM). Nowadays, the ultra-sharp tips with diameters lower than 100 nm are mostly used for electron guns with cathodes operating at a room temperature. This kind of free electron source has proven to have the highest source brightness accompanied with the lowest energy spread compared to common ZrO/W emitters.



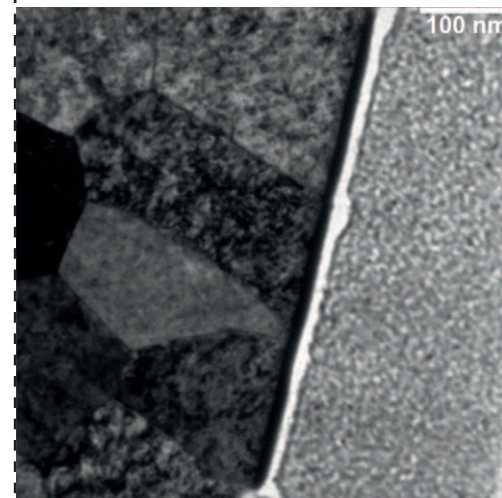
An I-V plot representing the current-voltage behavior of the clean tungsten tip (left) along with the emission pattern (right) measured in diode configuration with YAG scintillator showing beam profile.

WHAT YOU WILL BENEFIT FROM

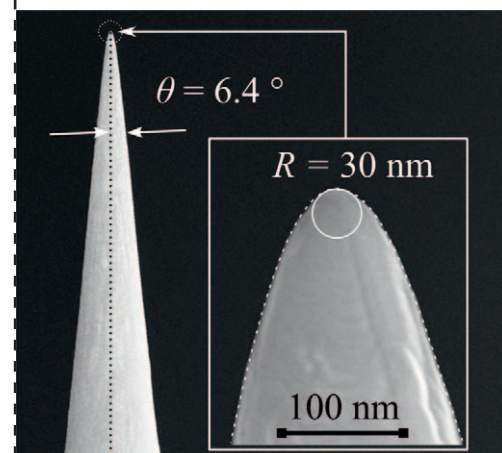
- More than 20 years de sign experience.
- Short production cycle.
- From science through R&D, to final product.
- Design labs using high-tech prototype production technology.



The macroscopic view of the example nanotip, made of a polycrystalline W.



Section of the polycrystalline tungsten tip showing crystalline structure and the surface oxide layer created during the etching. The layer thickness is approximately from 10 to 15 nanometers.



The detailed view of the example nanotip, made of a polycrystalline 0.3 tungsten wire using the preprogrammed two-step method.